


<b>Search Notes</b>  	<b>Application/Control No.</b>  10551039	<b>Applicant(s)/Patent Under Reexamination</b>  FUJITA ET AL.
	<b>Examiner</b>  NIKHIL SRIRAMAN	<b>Art Unit</b>  3664

SEARCHED			
Class	Subclass	Date	Examiner
700	245, 248, 249, 250, 253	12/20/2008	NS

SEARCH NOTES		
Search Notes	Date	Examiner
Consulted with Marc McDieunel	12/20/2008	
Assignee search on East, Inventor search on eDan		
NPL, including IEEE databases searched (see attached history)		
Reviewed submitted IDS references	7/12/2009	

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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